

Notice of References Cited			Application/Control No. 10/554,262	Applicant(s)/Patent Under Reexamination TESTIN ET AL.	
			Examiner PAULOS M. NATNAEL	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0018050	02-2002	Turner, William	345/169
*	B US-6,161,156	12-2000	Suzuki et al.	710/300
*	C US-6,999,059	02-2006	Kim, Chang-son	345/102
*	D US-7,379,393	05-2008	Morykwas et al.	368/10
*	E US-7,209,187	04-2007	Mears et al.	348/730
*	F US-6,464,633	10-2002	Hosoda et al.	600/178
*	G US-6,289,466	09-2001	Bayramoglu et al.	713/310
*	H US-5,929,943	07-1999	Bell et al.	348/730
*	I US-2002/0158813	10-2002	Kiyokawa et al.	345/7
*	J US-6,561,668	05-2003	Katayama et al.	362/85
*	K US-6,161,944	12-2000	Leman, Michael V.	362/276
*	L US-5,379,201	01-1995	Friedman, Arthur S.	362/191
*	M US-5,091,873	02-1992	Araki, Shigeharu	361/681

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.